

# **ESDA6V1-4F1**

# QUAD TRANSIL™ ARRAY FOR ESD PROTECTION

# A.S.D.™

# **APPLICATIONS**

Where transient overvoltage protection in ESD sensitive equipment is required, such as :

- Computers
- Printers
- Communication systems
- GSM handsets and accessories
- Other telephone sets
- Set top boxes

#### **DESCRIPTION**

The ESDA6V1-4F1 is a 4-bit wide monolithic suppressor designed to protect against ESD components which are connected to data and transmission lines.

It clamps the voltage just above the logic level supply for positive transients, and to a diode forward voltage drop below ground for negative transients.

# **FEATURES**

- 4 Unirectional transil functions
- Breakdown voltage: V<sub>BR</sub> = 6.1Vmin
- Low leakage current < 10 μA</li>
- Very low PCB space consuming

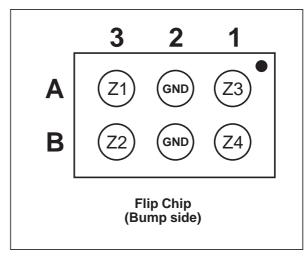
# **BENEFITS**

- > ± 15kV ESD Protection
- High integration
- Suitable for high density boards

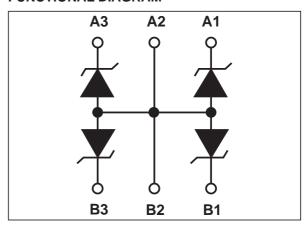
# COMPLIES WITH THE FOLLOWING STAN-DARDS:

- IEC61000-4-2: Level 4 15 kV (air discharge) 8 kV (contact discharge)

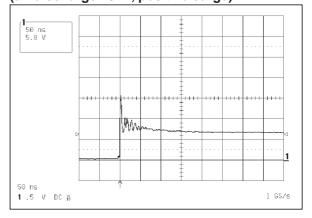
- MIL STD 883E-Method 3015-6: class3 (Human body model)



#### **FUNCTIONAL DIAGRAM**



# ESD RESPONSE TO IEC61000-4-2 (air discharge 16kV, positive surge)



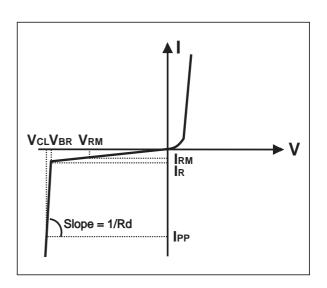
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# **ABSOLUTE MAXIMUM RATINGS** $(T_{amb} = 25$ °C)

| Symbol           | Test conditions  | Value            | Unit |
|------------------|--|------------------|------|
| V <sub>PP</sub>  | ESD discharge - MIL STD 883E - Method 3015-6<br>IEC61000-4-2 air discharge<br>IEC61000-4-2 contact discharge | ±25<br>±15<br>±8 | kV   |
| P <sub>PP</sub>  | Peak pulse power (8/20μs)  | 150              | W    |
| Tj               | Junction temperature   | 150              | °C   |
| T <sub>stg</sub> | Storage temperature range  | -55 to +150      | °C   |
| T <sub>L</sub>   | Lead solder temperature (10 seconds duration)  | 260              | °C   |
| Top              | Operating temperature range  | -40 to +85       | °C   |

# **ELECTRICAL CHARACTERISTICS** (T<sub>amb</sub> = 25°C)

| Symbol          | Parameter                       |
|-----------------|---------------------------------|
| $V_{RM}$        | Stand-off voltage               |
| $V_{BR}$        | Breakdown voltage               |
| V <sub>CL</sub> | Clamping voltage                |
| I <sub>RM</sub> | Leakage current                 |
| I <sub>PP</sub> | Peak pulse current              |
| αΤ              | Voltage temperature coefficient |
| С               | Capacitance per line            |
| Rd              | Dynamic impedance               |
| V <sub>F</sub>  | Forward voltage drop            |

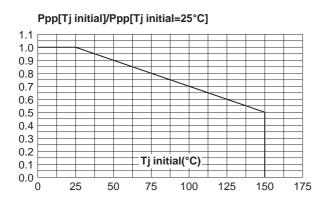


|             | VE   | BR @ | I <sub>R</sub> | I <sub>RM</sub> @ | V <sub>RM</sub> | Rd     | αΤ                   | С       |
|-------------|------|------|----------------|-------------------|-----------------|--------|----------------------|---------|
| Type        | min. | max. |                | max.              |                 | typ.   | max                  | max     |
| Туре        |      |      |                |                   |                 | note 1 | note 2               | 0V bias |
|             | V    | V    | mA             | μΑ                | V               | mΩ     | 10 <sup>-4</sup> /°C | pF      |
| ESDA6V1-4F1 | 6.1  | 7.2  | 1              | 10                | 5               | 350    | 6                    | 250     |

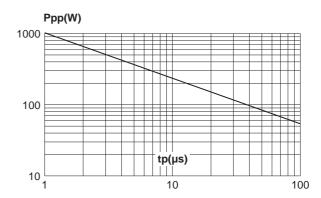
Note 1: Square pulse IPP = 15A, tp =  $2.5\mu s$ Note 2:  $\Delta VBR = \alpha T * (Tamb - 25) * VBR(25°C)$ 

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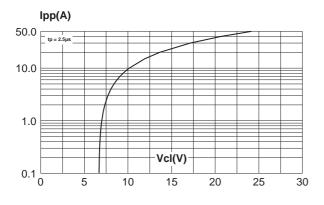
**Fig. 1:** Peak power dissipation versus initial junction temperature



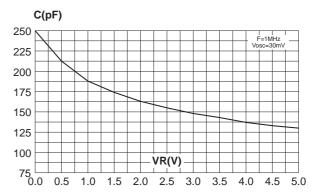
**Fig. 2:** Peak pulse power versus exponential pulse duration (Tj initial = 25°C)



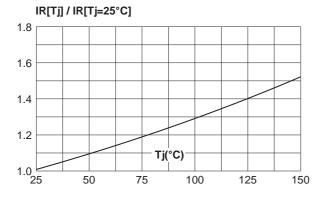
**Fig. 3:** Clamping voltage versus peak pulse current (Tj initial =  $25^{\circ}$ C). Rectangular waveform  $t_P = 2.5 \mu s$ .



**Fig. 4:** Capacitance versus reverse applied voltage (typical values).



**Fig. 5:** Relative variation of leakage current versus junction temperature (typical values).



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## **CALCULATION OF THE CLAMPING VOLTAGE**

## **USE OF THE DYNAMIC RESISTANCE**

The ESDA6V1-4F1 has been designed to clamp fast spikes like ESD. Generally the PCB designers need to calculate easily the clamping voltage  $V_{CL}$ . This is why we give the dynamic resistance in addition to the classical parameters.

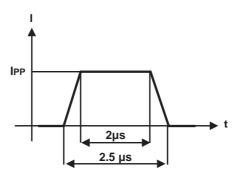
The voltage across the protection cell can be calculated with the following formula:

$$V_{CI} = V_{BR} + R_d \cdot I_{PP}$$

Where IPP is the peak current through the ESDA cell.

# DYNAMIC RESISTANCE MEASUREMENT

The short duration of the ESD has led us to prefer a more adapted test wave, as below defined, to the classical  $8/20~\mu s$  and  $10/1000~\mu s$  surges



2.5 µs duration measurement wave

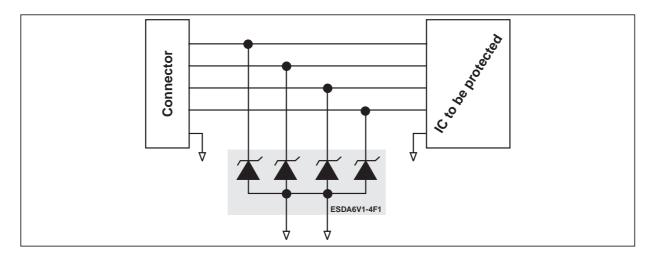
As the value of the dynamic resistance remains stable for a surge duration lower than 20µs, the 2.5µs rectangular surge is well adapted. In addition both rise and fall times are optimised to avoid any parasitic phenomenon during the measurement of Rd.

## **ESD PROTECTION WITH ESDA6V1-4F1**

With the focus of lowering the operation levels, the problem of malfunction caused by the environment is critical. Electrostatic discharge (ESD) is a major cause of failure in electronic system.

Transient Voltage Suppressors are an ideal choice for ESD protection and have proven capable in suppressing ESD events. They are capable of clamping the incoming transient to a low enough level such that damage to the protected semiconductor is prevented. Surface mount TVS arrays offer the best choice for minimal lead inductance. They serve as parallel protection elements, connected between the signal line to ground. As the transient rises above the operating voltage of the device, the TVS array becomes a low impedance path diverting the transient current to ground.

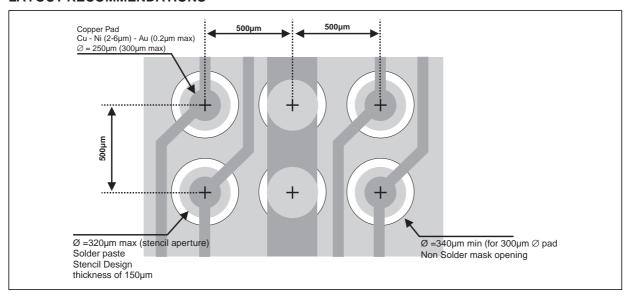
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The ESDA6V1-4F1 array is the ideal product for use as board level protection of ESD sensitive semiconductor components.

The Flip Chip package makes the ESDA6V1-4F1 device some of the smallest ESD protection devices available. It also allows design flexibility in the design of "crowded" boards where the space saving is at a premium. This enables to shorten the routing and can contribute to improved ESD performance.

#### LAYOUT RECOMMENDATIONS

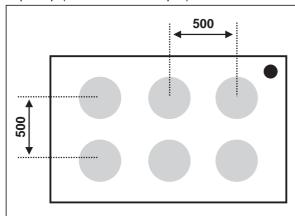


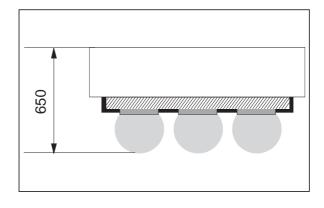
Circuit board layout is a critical design step in the suppression of ESD induced transients. The following guidelines are recommended :

- The ESDA6V1-4F1 should be placed as close as possible to the input terminals or connectors.
- Minimise the path length between the ESD suppressor and the protected device
- Minimise all conductive loops, including power and ground loops
- The ESD transient return path to ground should be kept as short as possible.
- Use ground planes whenever possible.

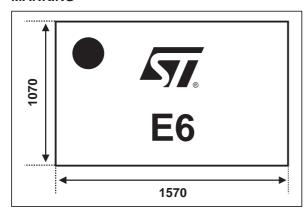
# **PACKAGE MECHANICAL DATA**

Flip Chip (all dimensions in µm)





#### **MARKING**



Die size:  $(1570 \pm 50) \times (1070 \pm 50)$ Die height (including bumps):  $650 \pm 40$ 

Bump diameter: 315 ± 50

Pitch: 500 ± 50

# **MARKING**

| Туре        | Marking | Delivery mode | Order Code  | Base qty |
|-------------|---------|---------------|-------------|----------|
| ESDA6V1-4F1 | E6      | Tape & reel   | ESDA6V1-4F1 | 5000     |

**Note:** For PCB design, assembly recommendations and packing information please refer to Application note AN1235. ("Flip-Chip: Package Description and recommendations for use")

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